

ICS 31.200
CCS L 56



**NATIONAL STANDARD OF THE
PEOPLE'S REPUBLIC OF CHINA**

GB/T 19403.1-2003

**Semiconductor devices -- Integrated Circuits -- Part 11: Section
1: Internal visual examination for semiconductor integrated
circuit (excluding hybrid circuits)
(English Translation)**

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Table of Contents

What this standard covers	1
Document data	2

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This standard specifies the IC 's internal materials, structures and processes, validation and conformance with applicable regulatory requirements. Should normally be sealed in the sealing cap or 100% of the device before the internal visual inspection to detect the device may cause failure during normal use of internal defects and eliminate the corresponding device. This test can also be sampling method used before the sealing cap to determine Zhifang quality control for semiconductor devices and operating effectiveness of the program.

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